

A statistical method to identify main contributing tolerances in assemblability studies based on convex hull techniques

P. Ziegler, S. Wartzack

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Lehrstuhl für

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Prof. Dr.-Ing. Sandro Wartzack



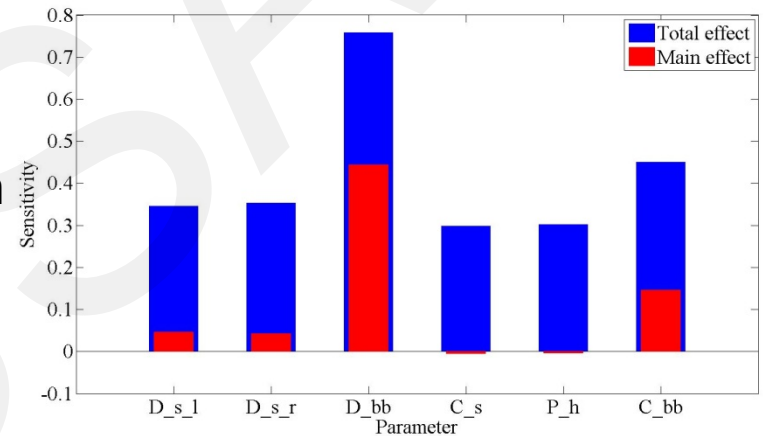
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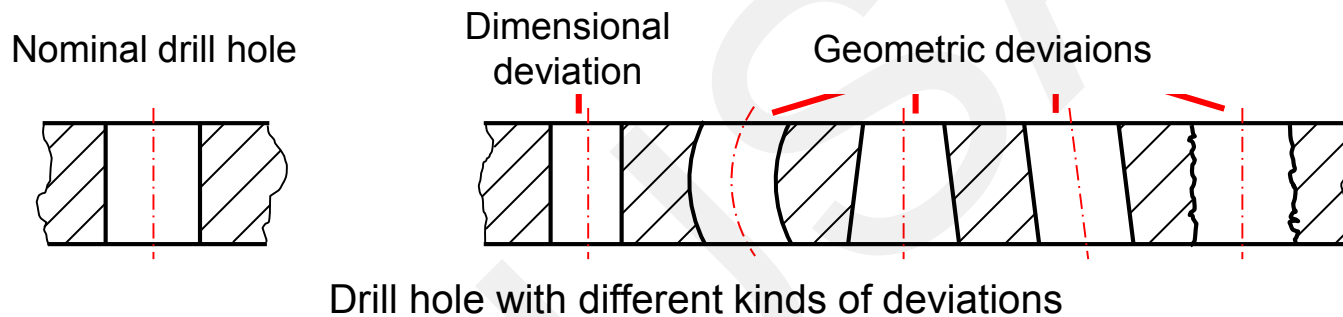
Sensitivity Analysis for Assemblability

Table of Contents

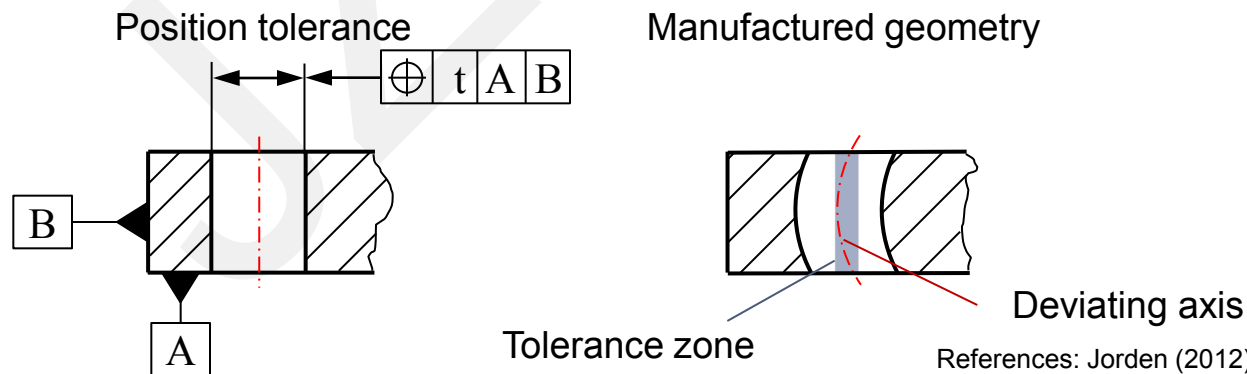
- **Tolerances**
- **The need for model free SA in Tolerancing**
 - Motivation
 - Methods in Tolerancing
- **Mathematical deviation representation**
 - Deviation Domain
 - Assemblability: Clearance Domain
- **Sensitivity Analysis**
 - Global Sensitivity Analysis
 - Variance-based Sensitivity Analysis
 - Basis for model free SA: Deviation Quality Measure
- **Application Example Pin-Hole**
 - Framework
 - Results
- **Summary & Outlook**



Axiom of manufacturing imprecision: All manufacturing processes are inherently imprecise and produce parts that vary.



Tolerances restrict the geometric deviations of parts with respect to the nominal geometry.



References: Jorden (2012), Srinivasan (1999)

The need for model free SA in Tolerancing

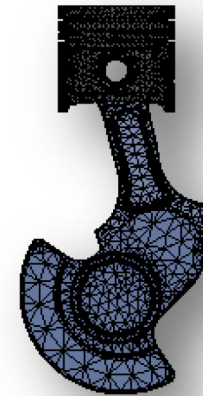
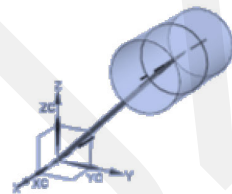
Motivation



Simulation Level of Detail



Switch of
representation
model?







There is a need for model free sensitivity analysis in tolerancing!

The need for model free SA in Tolerancing

Methods in Tolerancing

„Sensitivity analysis should be quantitative, global and model free“

SA Methods in Tolerancing	Quant.	Global	Model free*
High-Low-Median (HLM)			
Arithmetic Contributor			
Statistical Contributor			
Derivative-based (Wu)			
Variance-based (Stockinger/Walter)			
Variance/Density-based (Caniou)			

*For tolerance simulations, model free can be interpreted as „independent of mathematical deviation representation“

Reference: Saltelli and Tarantola (2002)

Mathematical deviation representation

Deviation Domain

Deviation Representation

Linearized homogeneous transformation matrices

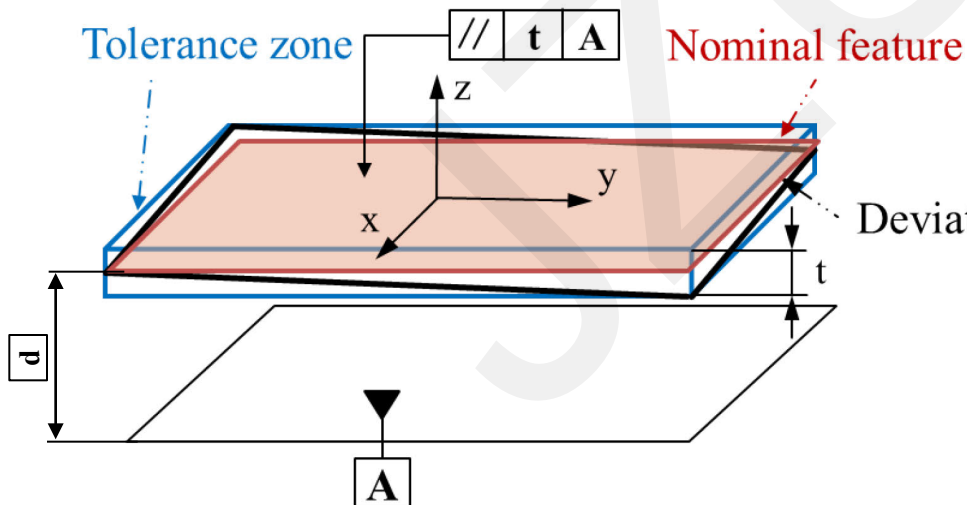
$$T^{lin}(\mathbf{x}, \boldsymbol{\theta}) = \begin{bmatrix} 1 & -\theta_1 & \theta_2 & x_1 \\ \theta_1 & 1 & -\theta_3 & x_2 \\ -\theta_2 & \theta_3 & 1 & x_3 \\ 0 & 0 & 0 & 1 \end{bmatrix}$$

Tolerance Representation

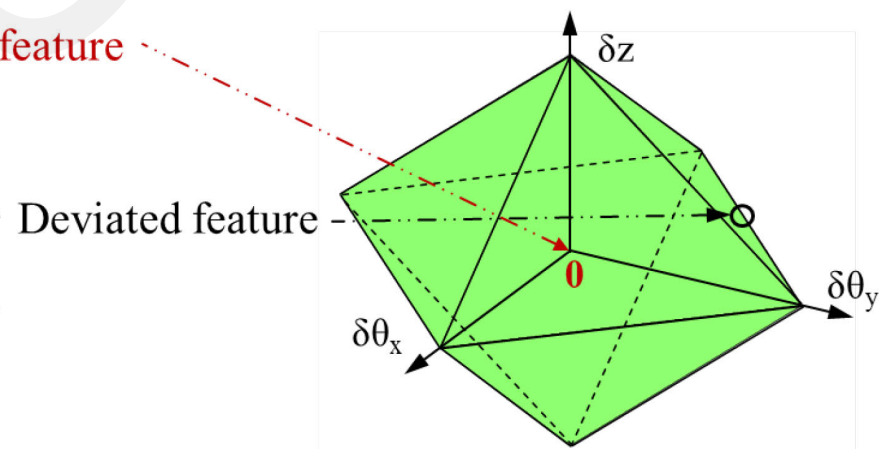
constraints for the transformation parameters $(\mathbf{x}, \boldsymbol{\theta})$

$$\max_{\mathbf{u} \in f} \|(T^{lin}(\mathbf{x}, \boldsymbol{\theta}) - I) \cdot \mathbf{u}\| \leq \frac{t}{2}$$

Feature with tolerance



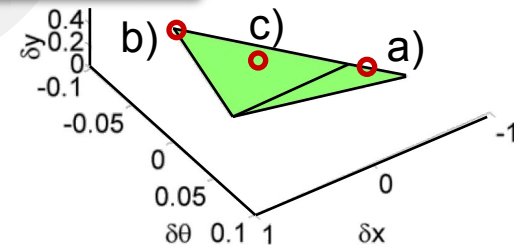
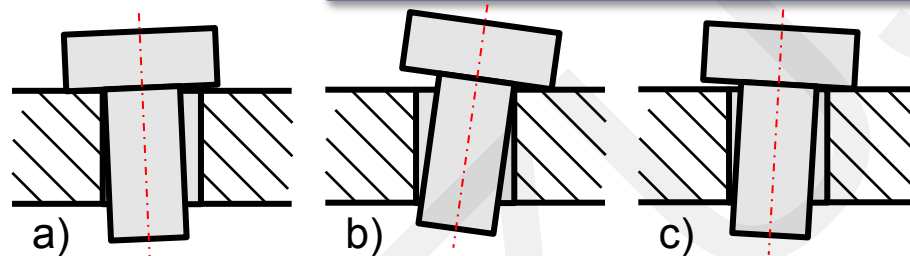
Abstract deviation space



Clearance Representation

The Clearance Domain C_{p_i, p_j}^{dev} consists of all transformation parameters (x, θ) for relative positions of two deviated parts considering assembly constraints.

Example: Nominal Pin & Hole (2D)



Assemblability Measure: Relative Clearance Domain Volume

Measure for all relative positions of p_i and p_j for two deviated parts.

$$\frac{|C_{p_i, p_j}^{dev}|}{|C_{p_i, p_j}^{nom}|}$$

Measure for all relative positions of p_i and p_j for the nominal geometry.

Sensitivity Analysis

Global Sensitivity Analysis

„Sensitivity analysis studies the relationships between information flowing in and out of the model“

A. Saltelli



Input Parameter



Model

Output Parameter

Local and Global Sensitivity Analysis in Tolerancing

Local methods

Consider an individual
(deviating) feature

Global methods

Consider a feature with tolerance
(and deviation distribution)

Reference: Saltelli et al (2000)

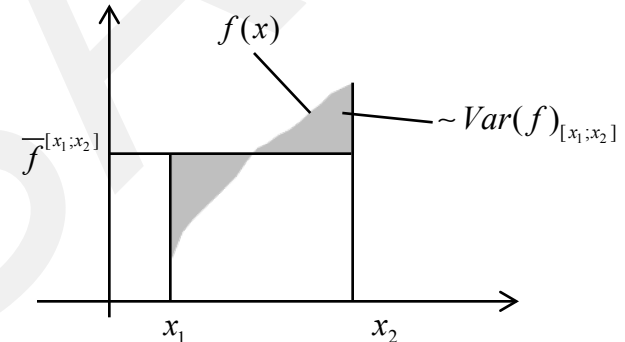
Sensitivity Analysis

Variance-based Sensitivity Analysis

Well established global method: variance-based SA

Let f be a generic model $f: (X_1, \dots, X_n) \rightarrow Y$ with random variables $X_i \in [0; 1]$. The variance $V(Y)$ then decomposes to

$$V(Y) = E(V(Y|X_i)) + V(E(Y|X_i)),$$



where $E(Y|X_i)$ denotes the conditional expectation with respect to X_i and $V(Y|X_i)$ the conditional variance with respect to X_i . The main effect sensitivity S_i and total effect sensitivity S_{T_i} of the random variable X_i is defined as

$$S_i = \frac{V(E(Y|X_i))}{V(Y)} \quad \text{and} \quad S_{T_i} = 1 - \frac{V(E(Y|\mathbf{X}_{\sim i}))}{V(Y)},$$

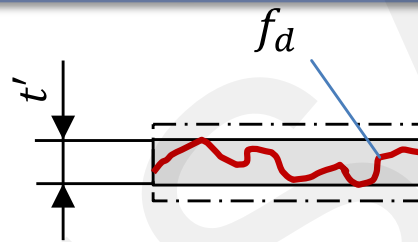
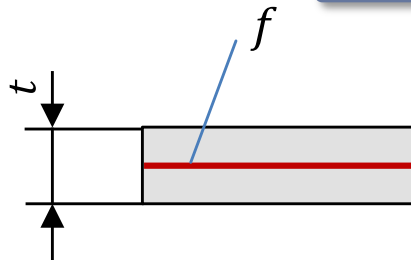
where $\mathbf{X}_{\sim i}$ denotes all input random variables aside from X_i .

Reference: Saltelli et al (2008)

Sensitivity Analysis

Basis for model free SA: Deviation Quality Measure

Deviation Quality Measure λ



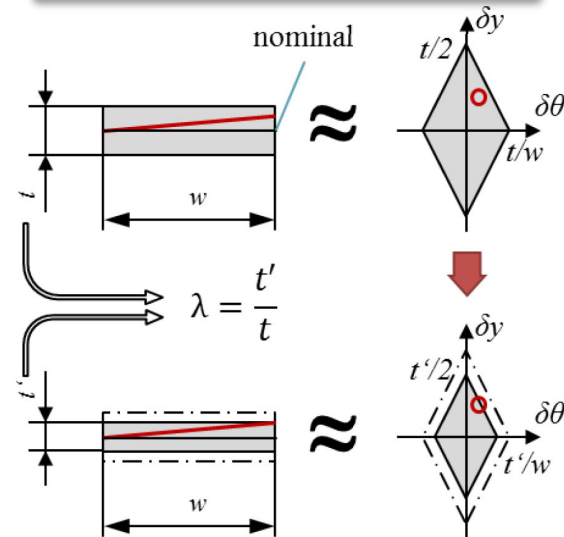
$$\lambda_t(f_d) = \frac{t'}{t}$$

Calculation for Deviation Domains

$$\lambda(\mathbf{x}, \boldsymbol{\theta}) = \frac{2}{t} \max_{\mathbf{u} \in f} \|(T^{lin}(\mathbf{x}, \boldsymbol{\theta}) - I) \cdot \mathbf{u}\|$$

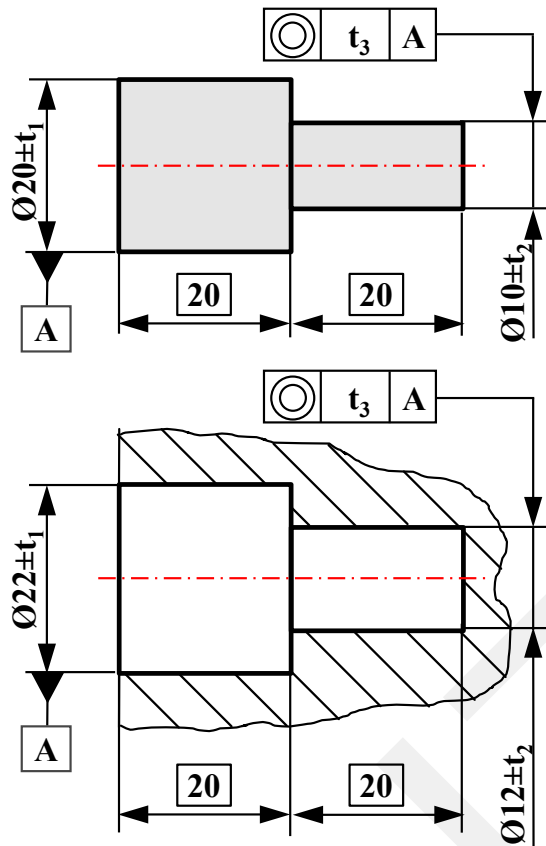
- λ is homogeneous in $(\mathbf{x}, \boldsymbol{\theta})$
- $\lambda(\mathbf{0}, \mathbf{0}) = 0$
- $\lambda(\mathbf{x}, \boldsymbol{\theta}) = 1 \Rightarrow (\mathbf{x}, \boldsymbol{\theta}) \in \partial DD$

Example for an axis



Reference: Ziegler (2013)

Application Example Pin-Hole

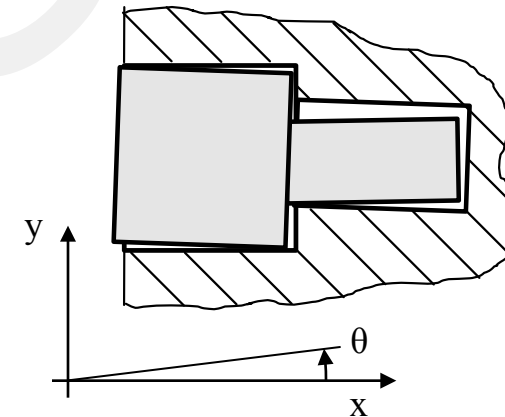


Tolerances

- 6 Tolerances, 4 dimensional and 2 geometric
- All tolerance values: 1 mm
- λ_i uniform distributed

Clearance Estimation

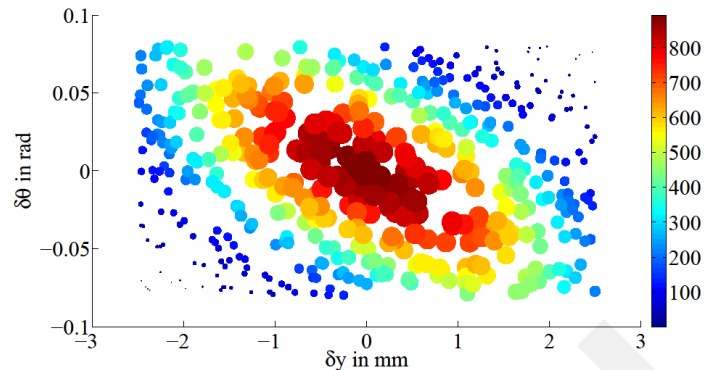
8 Control Points (vertices of pin cylinders) for collision detection
 → 8 constraints for transformation parameters (y, θ)



Application Example Pin-Hole Results

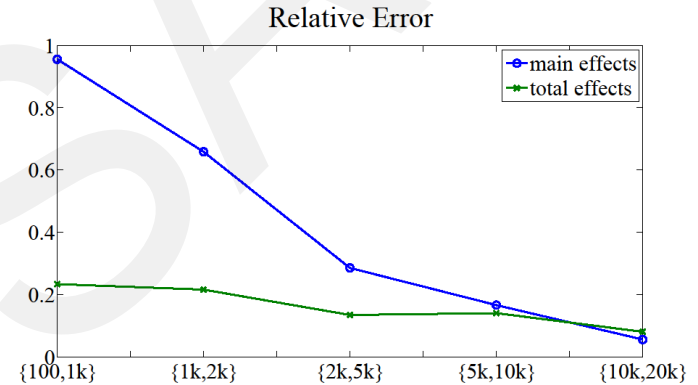
Clearance estimation

Few not mountable systems ($\leq 10\%$)

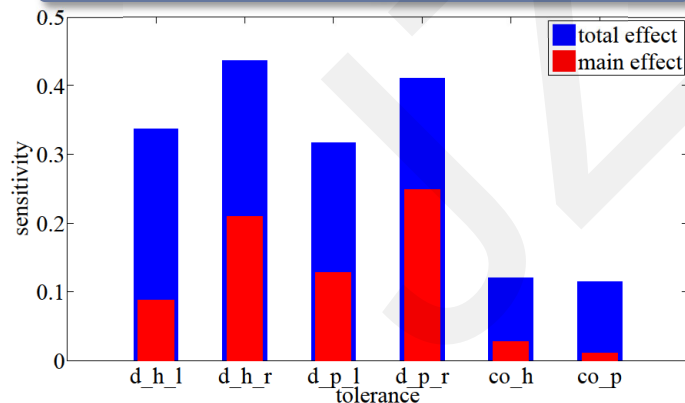


Monte Carlo Sample Size

Good results for 10,000+ SA-Samples



Sensitivity results



Arguments for the method

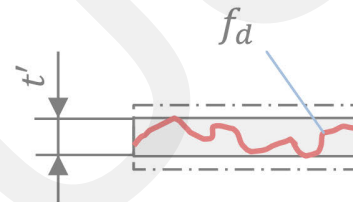
- The strong interactions between tolerances make a global SA method necessary for a realistic tolerance ranking
- As usually just few systems cannot be assembled, the upper left condition is mostly fulfilled

Sensitivity Analysis

Requirements: Quantitative,
Global and **Model free**

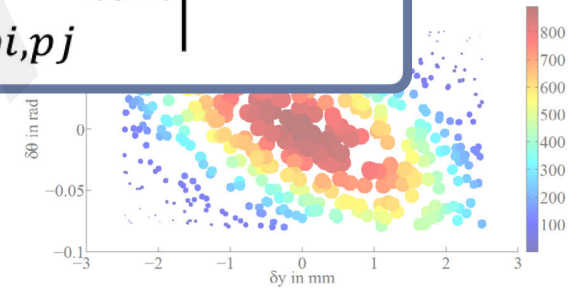
Deviation Characteristic

$$\lambda_t(f_d) = \frac{t'}{t}$$



Assemblability

$$\frac{|C_{pi,pj}^{aev}|}{|C_{pi,pj}^{nom}|}$$



Outlook

Other global SA methods and
Deviation Representations

